

STD2NK70Z STD2NK70Z-1

N-channel 700V - 6Ω - 1.6 A - DPAK/IPAK Zener protected SuperMESHTM Power MOSFET

General features

Туре	V _{DSS}	R _{DS(on)}	I _D	Pw
STD2NK70Z	700V	7Ω	1.6A	45W
STD2NK70Z-1	700V	7Ω	1.6A	45W

- Extremely high dv/dt capability
- ESD improved capability
- 100% avalanche tested
- New high voltage benchmark
- Gate charge minimized



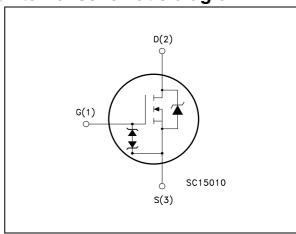
Description

The SuperMESH™ series is obtained through an extreme optimization of ST's well established strip-based PowerMESH™ layout. In addition to pushing on-resistance significantly down, special care is taken to ensure a very good dv/dt capability for the most demanding application. Such series complements ST full range of high voltage MOSFETs including revolutionary MDmesh™ products.

Applications

■ Switching application

Internal schematic diagram



Order codes

Part number	Marking	Package	Packaging
STD2NK70Z	D2NK70Z	D ² PAK	Tape & reel
STD2NK70Z-1	D2NK70Z	IPAK	Tube

July 2006 Rev 3 1/16

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1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage (V _{GS} = 0)	700	V
V _{DGR}	Drain-gate voltage (R_{GS} = 20 kΩ)	700	V
V _{GS}	Gate- source voltage	± 30	V
I _D	Drain current (continuous) at T _C = 25°C	1.6	Α
I _D	Drain current (continuous) at T _C = 100°C	1	А
I _{DM} ⁽¹⁾	Drain current (pulsed)	6.4	A
P _{tot}	Total dissipation at T _C = 25°C	45	W
	Derating factor	0.36	W/°C
V _{ESD(G-S)}	Gate source ESD (HBM-C = 100pF, R = 1.5 KΩ)	2000	V
dv/dt (2)	Peak diode recovery voltage slope	4.5	V/ns
T _{stg}	Storage temperature	55 to 150	°C
Tj	Max. operating junction temperature	33 10 130)

^{1.} Pulse width limited by safe operating area.

Table 2. Thermal data

Rthj-case	Thermal resistance junction-case max	2.78	°C/W
Rthj-amb	Thermal resistance junction-ambient max	100	°C/W
7)	Maximum lead temperature for soldering purpose	300	°C

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
I _{AS}	Avalanche current, repetitive or not-repetitive (pulse width limited by Tj Max)	1.6	А
E _{AS}	Single pulse avalanche energy (starting Tj=25°C, Id=lar, Vdd=50V)	110	mJ

^{2.} $I_{SD} \leq 1.6A$, di/dt $\leq 200A/\mu s$, $V_{DD} \leq V_{(BR)DSS}$, $Tj \leq T_{JMAX}$

Table 4. Gate-source zener diode

Symbol	Parameter	Test Condition	Min.	Тур.	Max	Unit
BV _{GSO}	Gate-source breakdown voltage	Igs= ±1mA (open drain)	30			Α

1.1 Protection features of gate-to-source zener diodes

The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

2 Electrical characteristics

(T_{CASE}=25°C unless otherwise specified)

Table 5. On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_D = 1 \text{mA}, V_{GS} = 0$	700			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	$V_{DS} = Max rating,$ $V_{DS} = Max rating @ 125°C$			1 50	μA μA
I _{GSS}	Gate body leakage current (V _{DS} = 0)	V _{GS} = ±20V		(±10	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 50\mu A$	3	3.75	4.5	٧
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10V, I _D = 0.8A		6	7	Ω

Table 6. Dynamic

	Symbol Parameter		Test conditions	Min.	Тур.	Max.	Unit
	g _{fs} ⁽¹⁾	Forward transconductance	$V_{DS} = 15V, I_D = 0.8A$		1.4		S
	C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} =25V, f=1 MHz, V _{GS} =0		280 35 6.5		pF pF pF
	C _{oss eq} ⁽²⁾ .	Equivalent output capacitance	V _{GS} =0, V _{DS} =0V to 560V		17		pF
-45018	t _{d(on)} t _r t _{d(off)} t _f	Turn-on delay time Rise time Turn-off delay time Fall time	V_{DD} =350 V, I_{D} = 0.8A, R_{G} =4.7 Ω , V_{GS} =10V (see Figure 14)		7 17 20 35		ns ns ns
Oh	Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V_{DD} =560V, I_D = 0.8A V_{GS} =10V (see Figure 15)		11.4 2 6.8		nC nC nC

^{1.} Pulsed: pulse duration=300µs, duty cycle 1.5%

^{2.} $C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} inceases from 0 to 80% V_{DSS}

Table 7. Source drain diode

I _{SD}	Parameter	Test conditions	Min	Тур.	Max	Unit
'SD	Source-drain current				1.6	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)				6.4	Α
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} =1.6A, V _{GS} =0			1.6	٧
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} =1.6A, di/dt = 100A/μs, V _{DD} =50V, Tj=25°C (see Figure 16)		334 918 5.5		ns μC A
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I_{SD} =1.6A, di/dt = 100A/ μ s, V_{DD} = 50V, Tj=150°C (see Figure 16)	*O	350 1050 6		ns μC Α
	dth limited by safe operating area pulse duration=300µs, duty cycle 1.5%					
	01(5)					

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

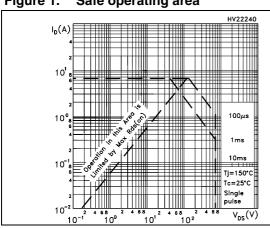


Figure 2. Thermal impedance

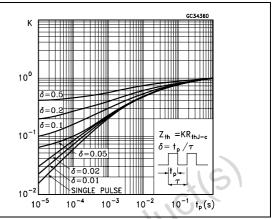
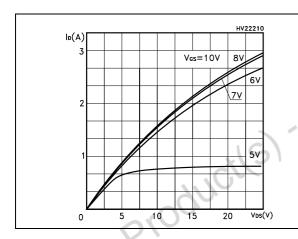


Figure 3. Output characterisics

Figure 4. Transfer characteristics



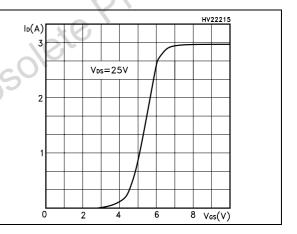
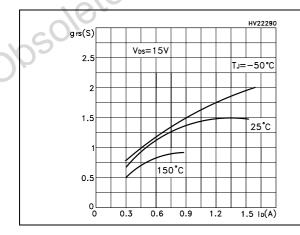


Figure 5. Transconductance

Figure 6. Static drain-source on resistance



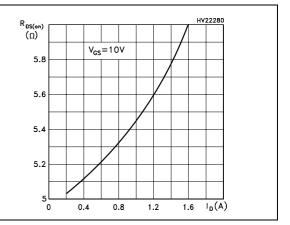


Figure 7. Gate charge vs gate-source voltage Figure 8. Capacitance variations

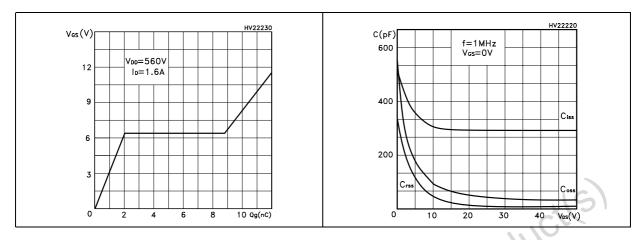


Figure 9. Normalized gate threshold voltage vs temperature

Figure 10. Normalized on resistance vs temperature

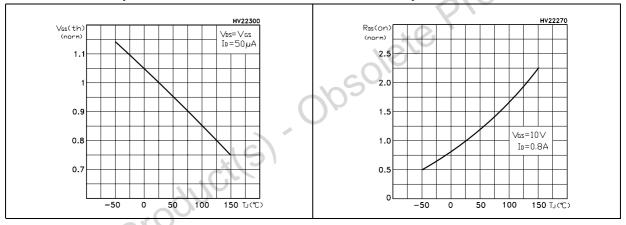


Figure 11. Source-drain diode forward characteristics

Figure 12. Normalized B_{VDSS} vs temperature

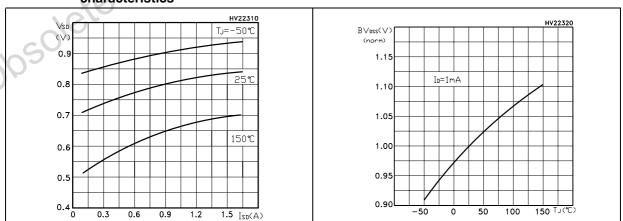
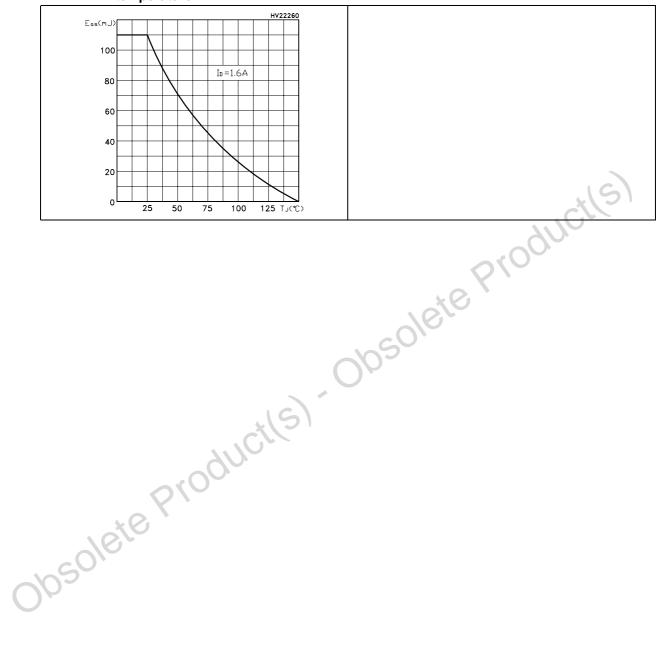


Figure 13. Maximum avalanche energy vs temperature



3 Test circuit

Figure 14. Switching times test circuit for resistive load

Figure 15. Gate charge test circuit

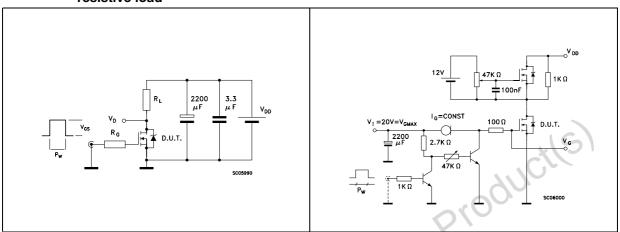


Figure 16. Test circuit for inductive load switching and diode recovery times

Figure 17. Unclamped Inductive load test circuit

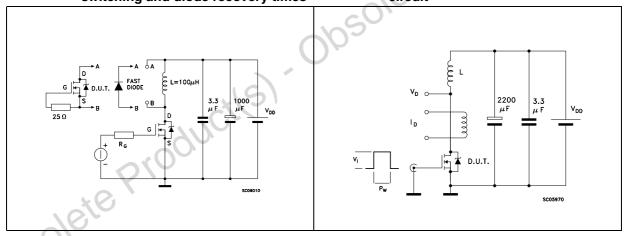
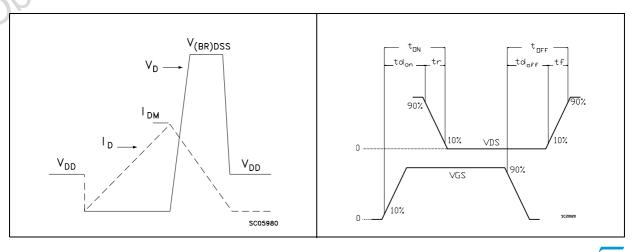


Figure 18. Unclamped inductive waveform

Figure 19. Switching time waveform



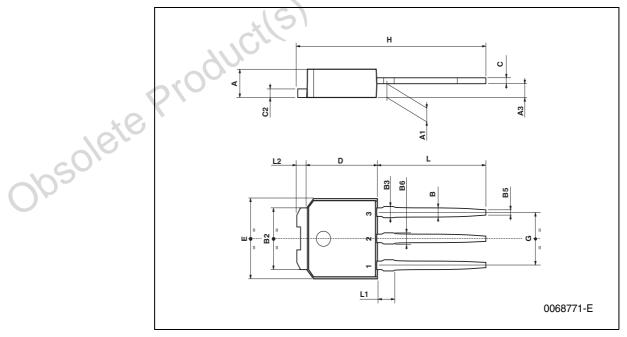
4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

Obsolete Product(s).

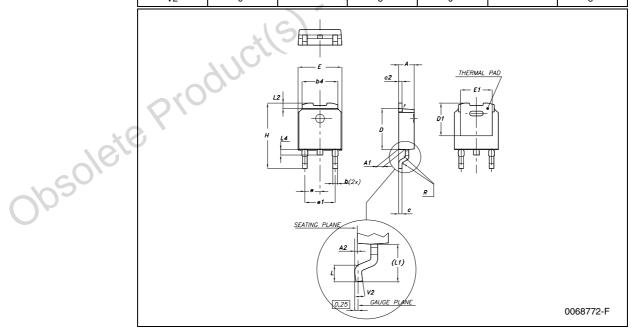
TO-251 (IPAK) MECHANICAL DATA

DIM.		mm			inch	
DIIVI.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
Α	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A3	0.7		1.3	0.027		0.051
В	0.64		0.9	0.025		0.031
B2	5.2		5.4	0.204		0.212
В3			0.85			0.033
B5		0.3			0.012	
B6			0.95			0.037
С	0.45		0.6	0.017) 0	0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
E	6.4		6.6	0.252		0.260
G	4.4		4.6	0.173		0.181
Н	15.9		16.3	0.626		0.641
L	9		9.4	0.354		0.370
L1	0.8		1.2	0.031		0.047
L2		0.8	1		0.031	0.039



DPAK MECHANICAL DATA

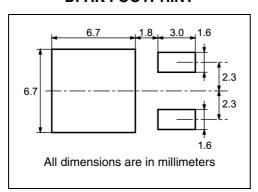
DIM.		mm.			inch			
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.		
Α	2.2		2.4	0.086		0.094		
A1	0.9		1.1	0.035		0.043		
A2	0.03		0.23	0.001		0.009		
В	0.64		0.9	0.025		0.035		
b4	5.2		5.4	0.204		0.212		
С	0.45		0.6	0.017		0.023		
C2	0.48		0.6	0.019		0.023		
D	6		6.2	0.236	1	0.244		
D1		5.1			0.200			
Е	6.4		6.6	0.252		0.260		
E1		4.7			0.185			
е		2.28			0.090			
e1	4.4		4.6	0.173		0.181		
Н	9.35		10.1	0.368		0.397		
L	1			0.039				
(L1)		2.8			0.110			
L2		0.8	. 60		0.031			
L4	0.6		1	0.023		0.039		
R		0.2	11		0.008			
V2	0°		8°	0°		8°		



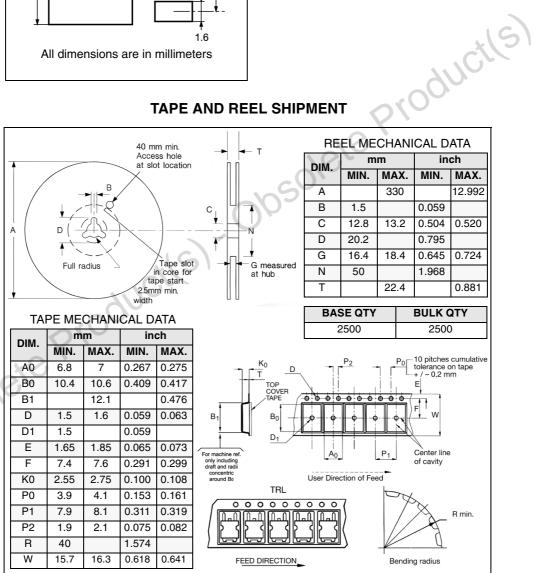
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Packaging mechanical data 5

DPAK FOOTPRINT



TAPE AND REEL SHIPMENT



6 Revision history

Table 8. Revision history

Date	Revision	Changes
21-Jan-2005	1	First Release
10-Jun-2005	2	Updated Figure 1: Safe operating area
13-Jul-2006	3	New template, no content change

Obsolete Product(s). Obsolete Product(s)

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